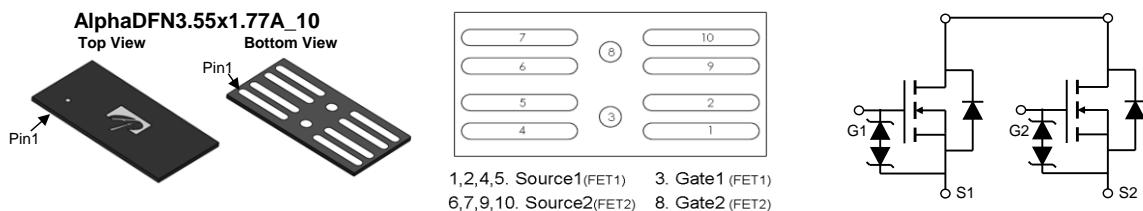


General Description	Product Summary
<ul style="list-style-type: none"> Trench Power MOSFET technology Low $R_{SS(ON)}$ With ESD protection to improve battery performance and safety Common drain configuration for design simplicity RoHS and Halogen-Free Compliant 	V_{SS} 12V $R_{SS(ON)}$ (at $V_{GS}=4.5V$) $< 2m\Omega$ $R_{SS(ON)}$ (at $V_{GS}=4.0V$) $< 2.1m\Omega$ $R_{SS(ON)}$ (at $V_{GS}=3.8V$) $< 2.2m\Omega$ $R_{SS(ON)}$ (at $V_{GS}=3.1V$) $< 2.7m\Omega$ $R_{SS(ON)}$ (at $V_{GS}=2.5V$) $< 3.3m\Omega$
Applications	Typical ESD protection
<ul style="list-style-type: none"> Battery protection switch Mobile device battery charging and discharging 	HBM Class 2
	



Orderable Part Number	Package Type	Form	Minimum Order Quantity
AOC3878	AlphaDFN3.55x1.77A_10	Tape & Reel	5000

Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Rating	Units
Source-Source Voltage	V_{SS}	12	V
Gate-Source Voltage	V_{GS}	± 8	V
Source Current(DC) ^{Note1}	I_S $ T_A=25^\circ C$	35	A
Source Current(Pulse) ^{Note2}	I_{SM}	130	
Power Dissipation ^{Note1}	P_D $ T_A=25^\circ C$	3.1	W
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	$^\circ C$

Thermal Characteristics

Parameter	Symbol	Typical	Units
Maximum Junction-to-Ambient	$t \leq 10s$	$R_{\theta JA}$	$^\circ C/W$
Maximum Junction-to-Ambient	Steady-State	40	$^\circ C/W$

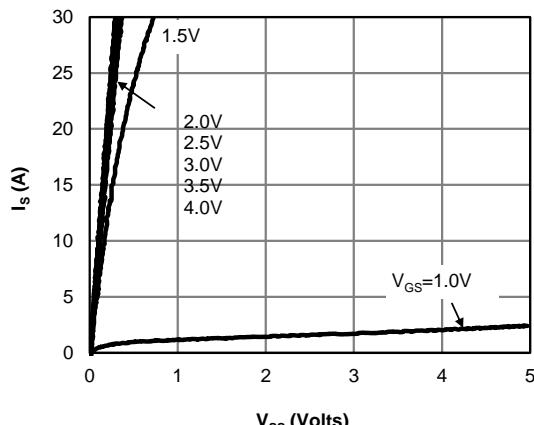
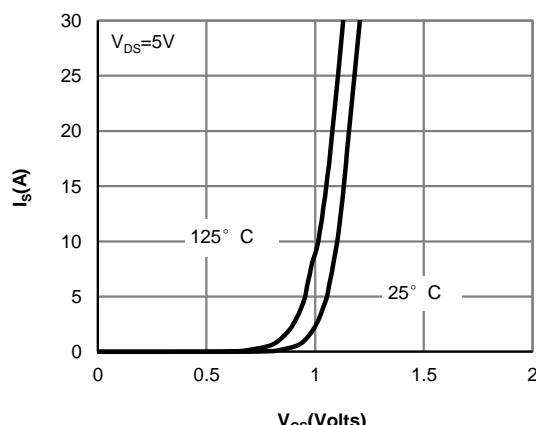
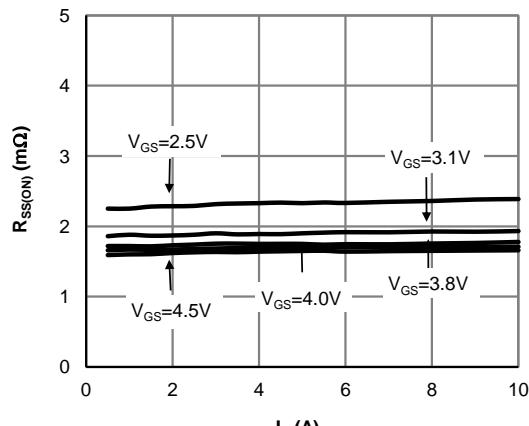
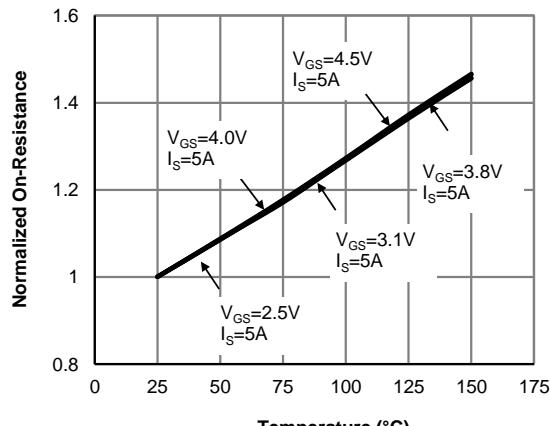
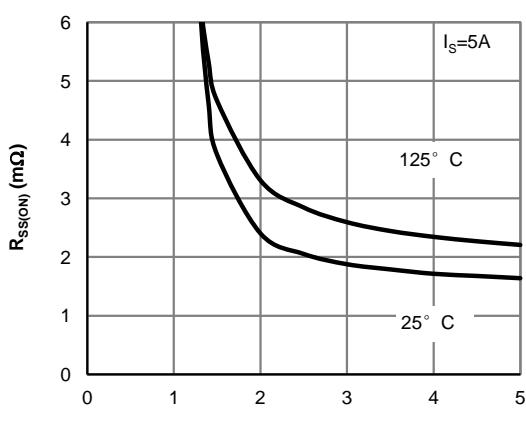
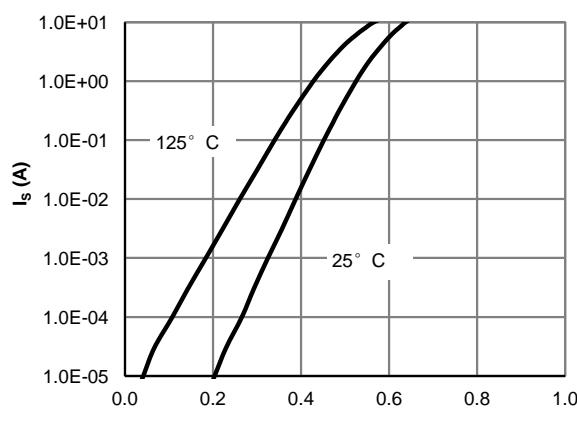
Note 1. I_S rated value is based on bare silicon. Mounted on 70mmx70mm FR-4 board.

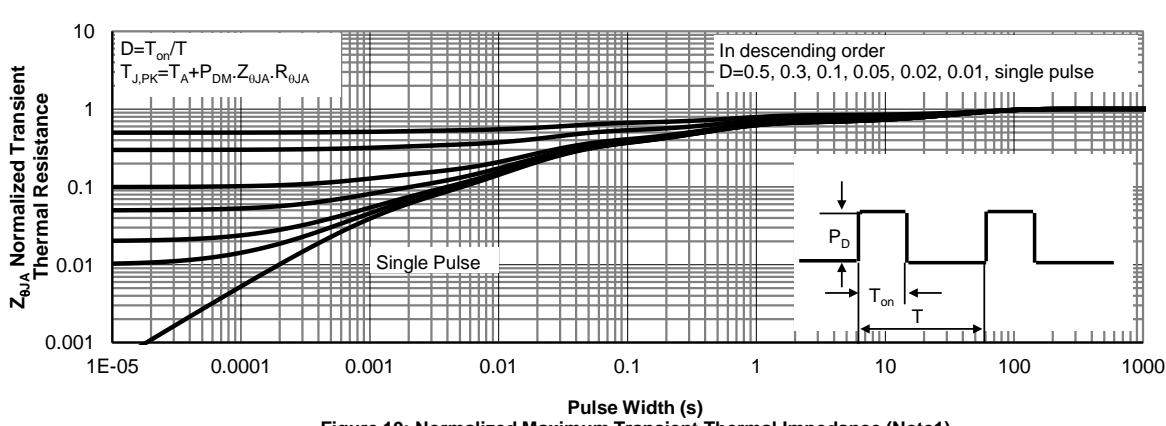
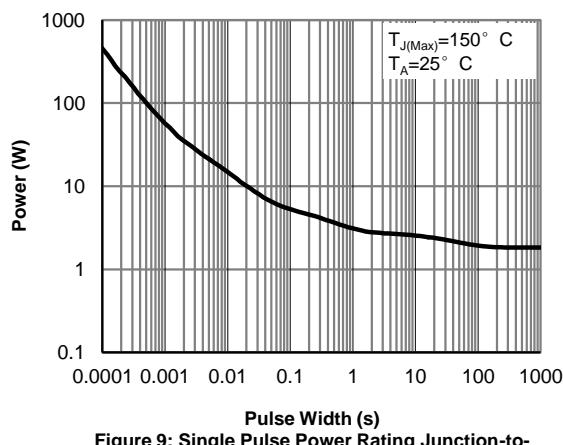
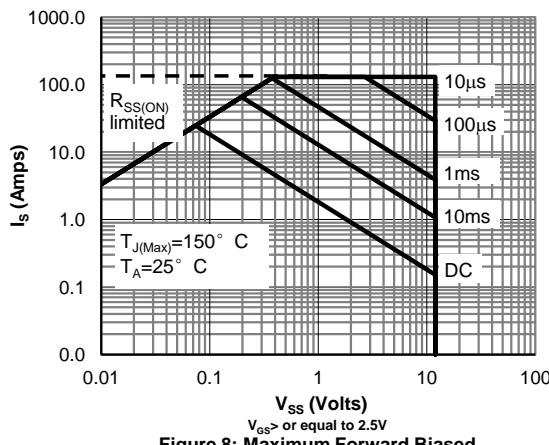
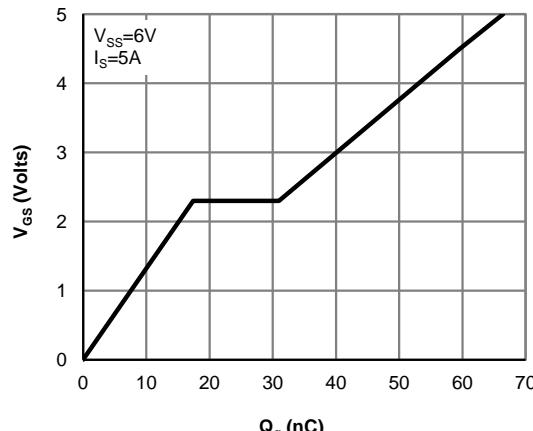
Note 2. PW <10 μs pulses, duty cycle 1% max.

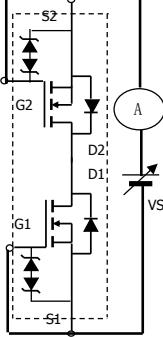
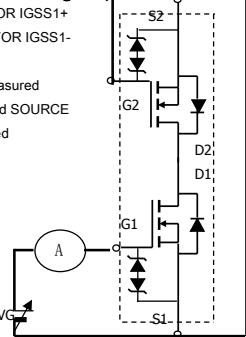
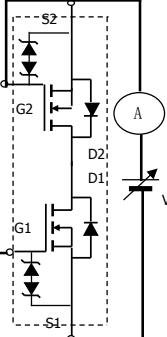
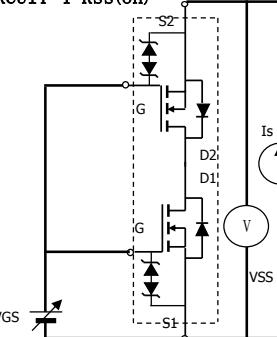
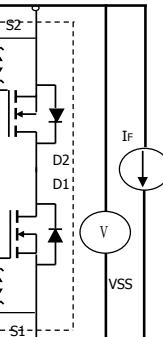
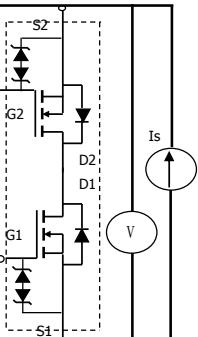
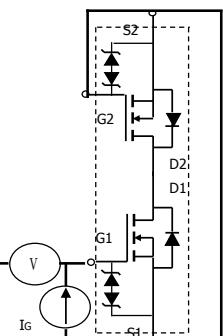
Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV _{SSS}	Source-Source Breakdown Voltage	I _S =250μA, V _{GS} =0V	Test Circuit 6	12		V
I _{SSS}	Zero Gate Voltage Source Current	V _{SS} =12V, V _{GS} =0V T _J =55°C	Test Circuit 1		1 5	μA
I _{GSS}	Gate leakage current	V _{SS} =0V, V _{GS} =±8V	Test Circuit 2		±10	μA
V _{GS(th)}	Gate Threshold Voltage	V _{SS} =V _{GS} , I _S =250μA	Test Circuit 3	0.4	0.7	1.1
R _{SS(ON)}	Static Source to Source On-Resistance	V _{GS} =4.5V, I _S =5A T _J =125°C	Test Circuit 4	1.1 1.5	1.65 2.25	2.0 2.7
		V _{GS} =4.0V, I _S =5A	Test Circuit 4	1.2	1.7	2.1
		V _{GS} =3.8V, I _S =5A	Test Circuit 4	1.25	1.75	2.2
		V _{GS} =3.1V, I _S =5A	Test Circuit 4	1.35	1.95	2.7
		V _{GS} =2.5V, I _S =5A	Test Circuit 4	1.6	2.3	3.3
g _{FS}	Forward Transconductance	V _{SS} =5V, I _S =5A	Test Circuit 3		55	S
V _{FSS}	Forward Source to Source Voltage	I _S =1A, V _{GS} =0V	Test Circuit 5		0.52	V
DYNAMIC PARAMETERS						
R _g	Gate resistance	f=1MHz		1.0		kΩ
SWITCHING PARAMETERS						
Q _g	Total Gate Charge	V _{G1S1} =4.5V, V _{SS} =6V, I _S =5A		60		nC
t _{D(on)}	Turn-On DelayTime	V _{G1S1} =4.5V, V _{SS} =6V, R _L =1.2Ω, R _{GEN} =3Ω Circuit8	Test	2.1		μs
t _r	Turn-On Rise Time			4.3		μs
t _{D(off)}	Turn-Off DelayTime			3.1		μs
t _f	Turn-Off Fall Time			14		μs

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 1: On-Region Characteristics

Figure 2: Transfer Characteristics

Figure 3: On-Resistance vs. Source Current and Gate Voltage

Figure 4: On-Resistance vs. Junction Temperature

Figure 5: On-Resistance vs. Gate-Source Voltage

Figure 6: Forward Source to Source Characteristics

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS


TEST CIRCUIT 1 Isss POSITIVE VSS FOR ISSS+ NEGATIVE VSS FOR ISSS- 	TEST CIRCUIT 2 Igss1,2 POSITIVE VGS FOR IGSS1+ NEGATIVE VGS FOR IGSS1- <p>When FET1 is measured between GATE and SOURCE of FET2 are shorted</p> 
TEST CIRCUIT 3 Vgs(off) <p>When FET1 is measured between GATE and SOURCE of FET2 are shorted</p> 	TEST CIRCUIT 4 Rss(on) 
TEST CIRCUIT 5 VF(ss)1,2 <p>When FET1 measured FET2 VGS=4.5V</p> 	TEST CIRCUIT 6 BVdss POSITIVE VSS FOR ISSS+ NEGATIVE VSS FOR ISSS- 
TEST CIRCUIT 7 BVgs01,2 POSITIVE VSS FOR ISSS+ NEGATIVE VSS FOR ISSS- <p>When FET1 is measured between GATE and SOURCE of FET2 are shorted</p> 	TEST CIRCUIT 8 Switching time 